

<b>Notice of References Cited</b>	Application/Control No. 09/965,824	Applicant(s)/Patent Under Reexamination CHANG, CHIEN LIANG	
	Examiner BRIAN P. YENKE	Art Unit 2614	Page 1 of 2

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	Examiner BRIAN P. YENKE	Art Unit 2614	Page 2 of 2

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